

# SPS EMC Software modules

Software modules for EMC emission and immunity standards and their requirements of specific hardware

Supported Windows Versions: Windows 10

# Basic software unit SPS TestManager

Framework for Basic EMC System software application

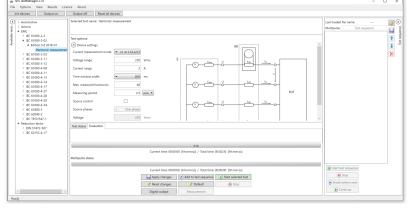


Fig. 1: Example screenshot

# Software module IEC 61000-3-2/-3/-11/-12

Automatic testing and measuring of harmonic emissions and flicker according to the following standards:

- ▲ IEC 61000-3-02
  - ▲ Edition 5.0 2018-01

Harmonic measurement

- ▲ IEC 61000-3-03
  - ▲ Edition 3.1 2017-05

Flicker measurement

- IEC 61000-3-11
  - ▲ Edition 2.0 2017-04

Flicker measurement

- ▲ IEC 61000-3-12
  - Edition 2.0 2011-05

Harmonic Measurement

IEC 61000-3-2:2018 Ed 5.0

Limits for harmonic current emissions, equipment input current ≤16A per phase IEC 61000-3-3:2017 Ed 3.1

Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems,

input current ≤16A per phase

IEC 61000-3-11:2017 Ed 2.0

Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems,

input current >16A and ≤75A

IEC 61000-3-12:2011 Ed 2.0

Limits for harmonic currents produced by equipment connected to public low-voltage systems.

input current >16A and ≤75A

## Integrated functions of the software module:

- Control of APS (power source) and AIS (harmonic analyser, flickermeter, line impedance simulating network)
- measurement of harmonics: Uh, Ih
- measurement of flicker values: Pst, Plt, dc, dmax, Tmax
- tabular and graphical display of measured values
- calculation of further values from the measured values
- predefined limits according to the standards
- evaluation according to the standards
- tabular and graphical version of test reports



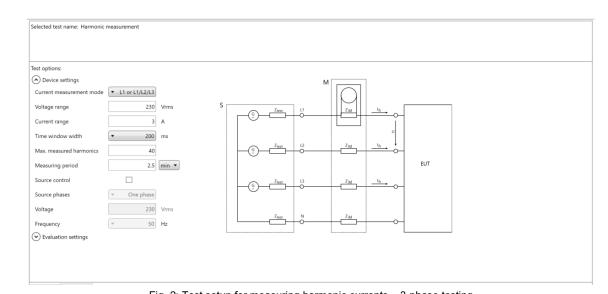


Fig. 2: Test setup for measuring harmonic currents – 3-phase testing

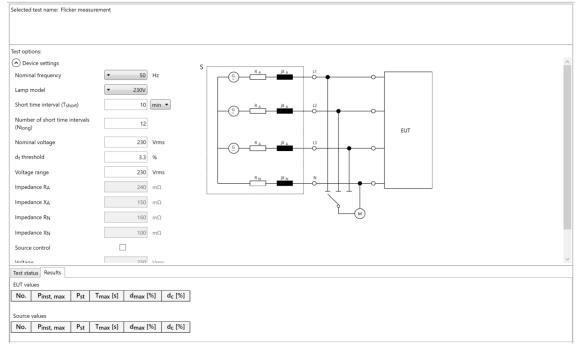


Fig. 3: Test setup for flicker measurements – 3-phase testing

#### required hardware:

- 4-quadrant amplifier APS
- measuring instrument AIS (harmonic analyser, flickermeter, line impedance simulating network)



Automatic testing according to IEC 61000-4-11:2020 Ed 3.0

- ▲ IEC 61000-4-11
  - ▲ Edition 2.0 2004-03
  - Voltage dips

With neutral

Without neutral - Method A Without neutral - Method B

Short interruptions Voltage variations

▲ Edition 2.1 2017-05

■ Voltage dips

With neutral

Without neutral - Method A Without neutral - Method B

Short interruptions Voltage variations

- ▲ Edition 3.0 2020-01
  - Voltage dips

With neutral

Without neutral - Method A

Without neutral - Method B

Short interruptions Voltage variations

Voltage dips, short interruptions and voltage variations immunity tests

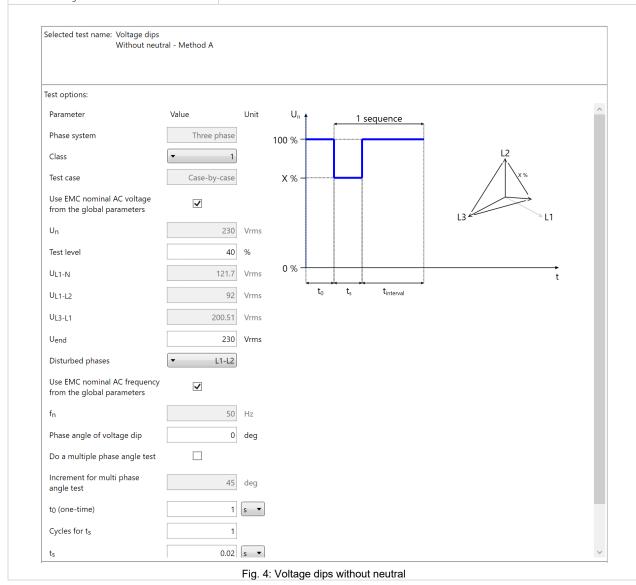
Integrated functions of the software module:

- control of APS amplifier
- sequential operation of defined pulses
- automatic capturing of the waveforms of voltage and current
- graphical documentation of the generated voltage dips and/or voltage changes in the test report

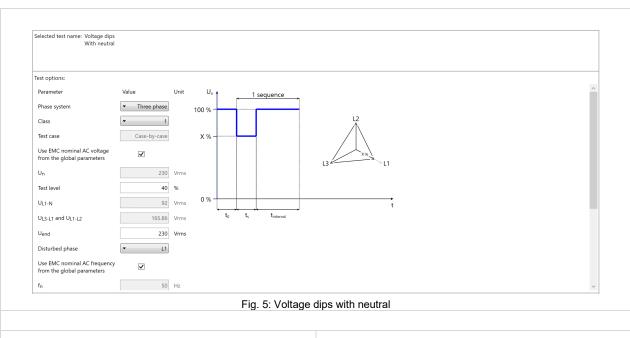
#### required hardware:

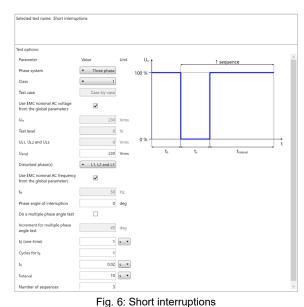
- 4-quadrant amplifier APS
- inrush current source ICS 500 if inrush current capability of APS is <500A see application note "Source inrush current capability of APS amplifiers -

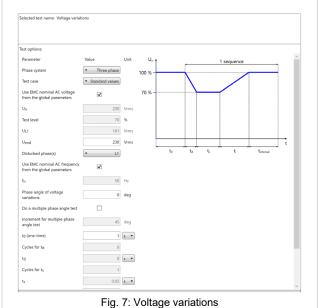
Power source version depending on the EUT: single (APS) or 3-phase model (DM /APS)













Automatic testing according to IEC 61000-4-13:2015 Ed 1.2

- ▲ IEC 61000-4-13
  - Edition 1.1 2009-07

Harmonic combination test flat curve

Harmonic combination test over swing

Test method "Sweep in frequencies"

Individual harmonics with a specified test level sequence Interharmonics with a specified test level sequence

Meister curve test

■ Complete test process

Class 1

Class 2

Class 3

■ Edition 1.2 2015-12

Harmonic combination test flat curve

Harmonic combination test over swing

Test method "Sweep in frequencies"

Individual harmonics with a specified test level sequence Interharmonics with a specified test level sequence

Meister curve test

■ Complete test process

Class 1

Class 2

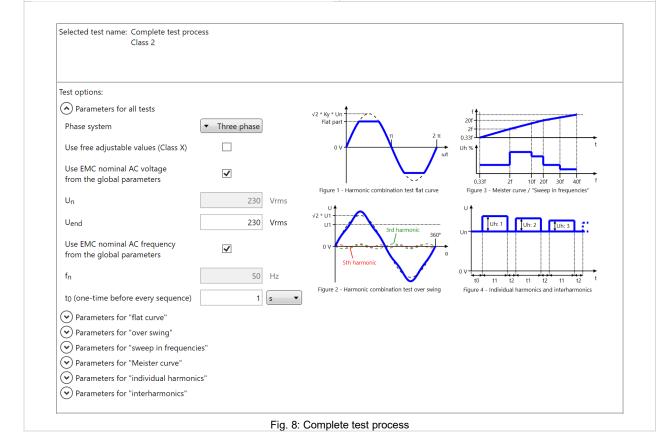
Class 3

Harmonics and interharmonics including mains signalling at a.c. power port, low frequency immunity tests

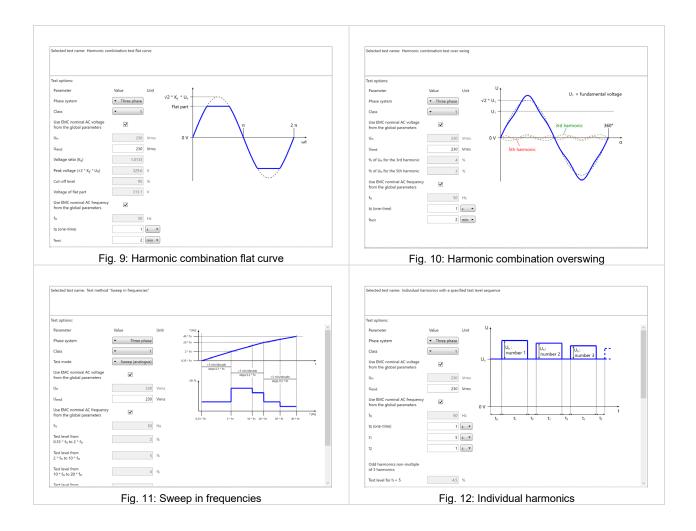
Integrated functions of the software module:

- control of APS amplifier
- harmonic combination test "flat curve" and "over swing"
- test method "sweep in frequencies"
- individual harmonics and interharmonics with specified test levels
- Meister curve test
- complete test process

Required hardware:









Automatic testing according to IEC 61000-4-14:2009 Ed 1.2

- **▲** IEC 61000-4-14
  - ▲ Edition 1.2 2009-08
    - Voltage fluctuation immunity test
      - Single-phase system

Class 2

Class 3

Class X

■ Three-phase system

Class 2

Class 3

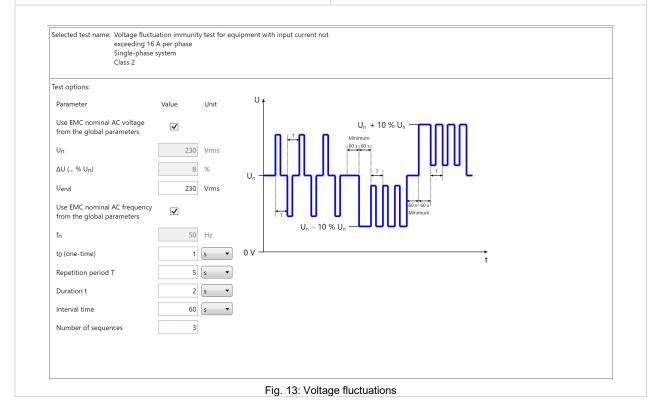
Class X

Voltage fluctuation immunity test for equipment with input current not exceeding 16 A per phase

Integrated functions of the software module:

- control of APS amplifier
- generation of voltage fluctuations as defined in IEC standard

Required hardware:





Automatic testing according to IEC 61000-4-17:2009 Ed 1.2

- **■** IEC 61000-4-17
  - ▲ Edition 1.2 2009-01
    - Ripple on d.c. input power port immunity test
      - 1 time the power frequency
      - 2 times the power frequency
      - 3 times the power frequency
      - 6 times the power frequency

Ripple on d.c. input power port immunity test

Integrated functions of the software module:

- control of APS amplifier
- generation of ripple on d.c. power supply as defined in IEC standard

Required hardware:

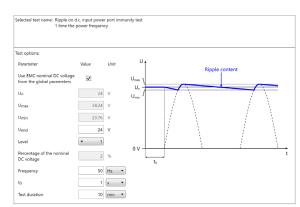


Fig. 14: Ripple with power frequency

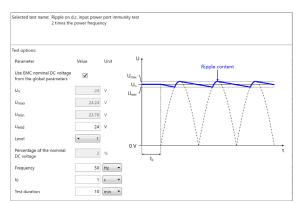


Fig. 15: Ripple with 2x power frequency

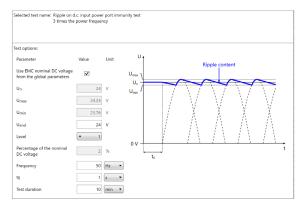


Fig. 16: Ripple with 3x power frequency

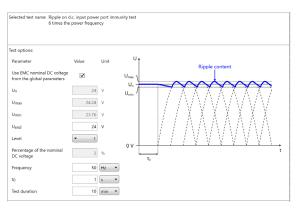


Fig. 17: Ripple with 6x power frequency



#### Software module IEC 61000-4-27 Automatic testing according to IEC 61000-4-27:2009 Ed 1.1 Unbalance, immunity test for equipment with input current not ▲ IEC 61000-4-27 exceeding 16 A per phase ▲ Edition 1.1 2009-04 Integrated functions of the software module: Unbalance, immunity test for equipment with input - control of APS amplifier ■ Test 1 - generation of unbalance immunity tests as defined in IEC Class 2 Class 3 Required hardware: Class X 4-quadrant amplifier APS (3-phase version DM /APS) ■ Test 2 Class 2 Class 3 Class X ■ Test 3 Class 2 Class 3 Class X Selected test name: Unbalance, immunity test for equipment with input current not exceeding 16 A per phase Test 1 Class 2 Test options: Value L1 L2 L3 L2 L3 L1 L3 L1 L2 Parameter Use EMC nominal AC voltage **~** from the global parameters 230 Un Vrms $\mathsf{U}_{\text{end}}$ 230 Vrms % of $U_n$ for $U_a$ 100 Ua 230 Vrms Angle of Ua 0 deg unbalance sequence 95.2 % of $U_{n}$ for $U_{b}$ Succession of three unbalance sequences of the test (the voltages Ua, Ub, Uc rotate) NOTE These figures apply to 50 Hz systems 218.96 Vrms Ub Angle of Ub 125 deg % of $U_n$ for $U_c$ 90 207 Vrms Angle of U<sub>C</sub> 240 deg Use EMC nominal AC frequency **~** from the global parameters 50 Hz t<sub>0</sub> (one-time) 1 s 30 s Duration t 180 s Time between sequences

Fig. 18: Unbalance



Automatic testing according to IEC 61000-4-28:2009 Ed 1.2

- ▲ IEC 61000-4-28
  - Edition 1.2 2009-04
    - Variation of power frequency, immunity test for equipment
      - Single-phase system

#### Test level 2

Test level 3

Test level 4

Test level X

Three-phase system

Test level 2

Test level 3

Test level 4

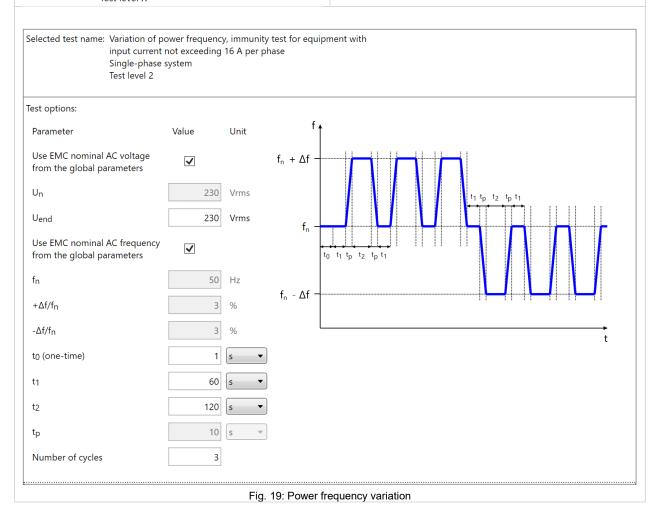
Test level X

Variation of power frequency, immunity test for equipment with input current not exceeding 16 A per phase

Integrated functions of the software module:

- control of APS amplifier
- generation of variation of power frequency immunity tests as defined in IEC standard

#### Required hardware:





Automatic testing according to IEC 61000-4-29:2000 Ed 1.0

- ▲ IEC 61000-4-29
  - ▲ Edition 1.0 2000-08

#### Voltage dips

Short interruptions Voltage variations Voltage dips, short interruptions and voltage variations on d.c. input power port immunity tests

Integrated functions of the software module:

- control of APS amplifier
- control of electronic switch EPS 100/4-29
- generation of voltage changes on d.c. power supply as defined in IEC standard

#### Required hardware:

- 4-quadrant amplifier APS for low impedance interruptions testing

electronic switch EPS 100/4-29 if high impedance interruptions testing is additionally required

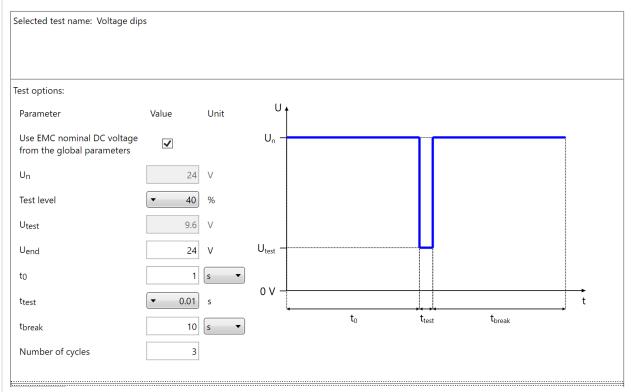


Fig. 20: Voltage dips

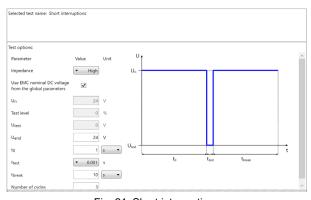


Fig. 21: Short interruptions

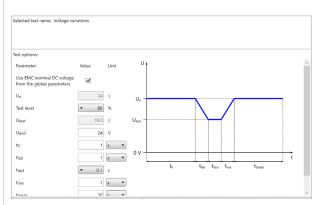


Fig. 22: Voltage variations



Automatic testing according to IEC 61000-4-34:2009 Ed 1.1

- ▲ IEC 61000-4-34
  - ▲ Edition 1.1 2009-11
    - Voltage dips
      - ▶ Single-phase system
      - Three-phase system
        - With neutral
        - ▶ Without neutral Method A
        - ▶ Without neutral Method B
    - Short interruptions
      - ▶ Single-phase system
      - Three-phase system

Class 1 - Case-by-case

Class 2 - 0 % during 250/300 cycles

Class 3 - 0 % during 250/300 cycles

Class X - 0 % during X cycles

- Voltage variations
  - ▶ Single-phase system
  - Three-phase system

Voltage test level 70 %

Voltage test level X

Voltage dips, short interruptions and voltage variations immunity tests for equipment with mains current more than 16 A per phase

Integrated functions of the software module:

- control of APS amplifier
- generation of voltage dips, short interruptions and voltage variations as defined in IEC standard
- sequential operation of defined pulses
- automatic capturing of waveforms of voltage and current
- graphical documentation of the generated voltage dips and/or voltage changes in the test report

#### Required hardware:

4-quadrant amplifier APS

Compliance testing for EUTs ≤ 50A requires the option 'Inrush current source' ICS 500 or minimum the 4-quadrant amplifier APS 15000.

For EUTs >50A minimum the 4-quadrant amplifier APS 30000 is required.

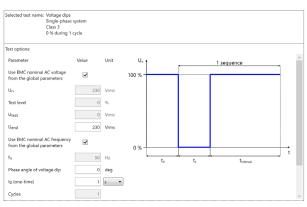


Fig. 23: Voltage dips 0%

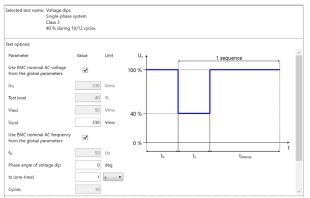


Fig. 24: Voltage dips 40%

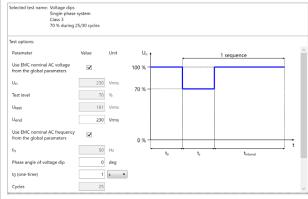


Fig. 25: Voltage dips 70%

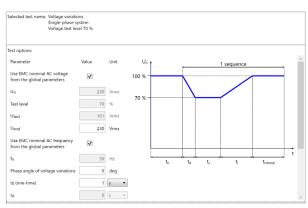
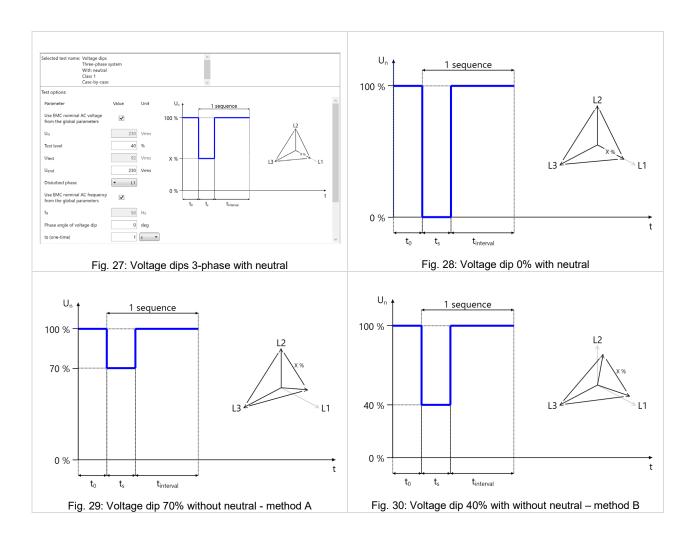


Fig. 26: Voltage variations

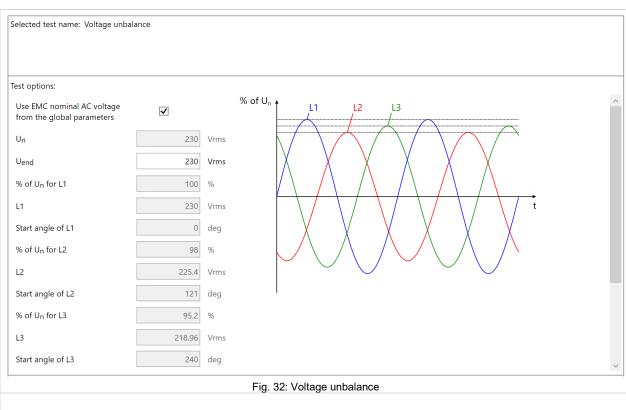


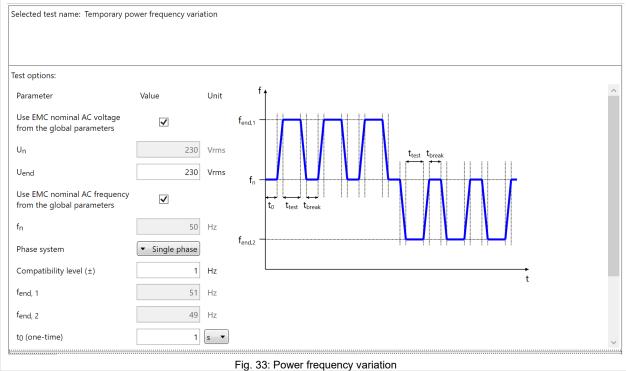




#### Software module IEC 61000-2-2 Automatic testing according to IEC 61000-2-2:2018 Ed 2.2 Compatibility levels for low-frequency conducted disturbances ▲ IEC 61000-2-2 and signalling in public low-voltage power supply systems ■ Edition 2.2 2018-05 Integrated functions of the software module: Harmonics - control of APS amplifier - generation of: 4.3 Harmonics Voltage unbalance - generation of: 4.6 Voltage unbalance Temporary power frequency variation - generation of: 4.8 Temporary power frequency variation Required hardware: 4-quadrant amplifier APS Selected test name: Harmonics Test options: U Parameter Value Unit Use EMC nominal AC voltage **√** from the global parameters 230 Un Vrms 360° Uend 230 Vrms 0 V Use EMC nominal AC frequency **~** from the global parameters 50 Phase system Single phase Long-term effect Effect duration L1 Disturbed phase(s) Use free adjustable values to (one-time) Test time 10 min ▼ factor k Odd harmonics (non-multiple of 3) Test level for h = 5Test level for h = 7Test level for h = 11 3.5 Test level for h = 13Test level for $17 \le h \le 37$ 2.27 \* (17 / h) - 0.27 % Fig. 31: Harmonics









Automatic testing according to IEC 61800-3:2017 Ed 3.0

- ▲ IEC 61800-3
  - ▶ Edition 2.1 2012-03
  - Edition 3.0 2017-02
    - Harmonics and commutation notches/voltage distortion
      - ▶ Single phase
      - ▶ Three phase
    - Voltage deviations, dips and short interruptions
      - Single phase
      - ▶ Three phase
    - Voltage unbalance and frequency variations
      - Single phase
      - ▶ Three phase

Adjustable speed electrical power drive systems

Integrated functions of the software module:

- control of APS amplifier
- 5.2 Basic immunity requirements low frequency disturbances
- 5.2.2 Harmonics and commutation notches/voltage distortion
- 5.2.3 Voltage deviations, dips and short interruptions
- 5.2.4 Voltage unbalance and frequency variations

#### Required hardware:

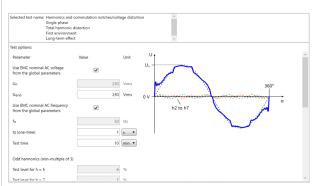


Fig. 34: Harmonics combination



Fig. 35: Individual harmonics

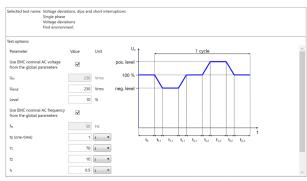


Fig. 36: Voltage deviations

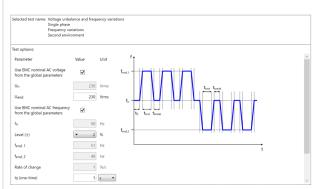
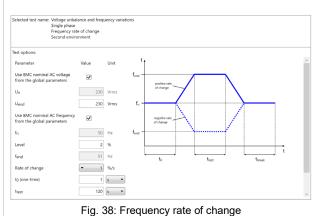


Fig. 37: Frequency variations



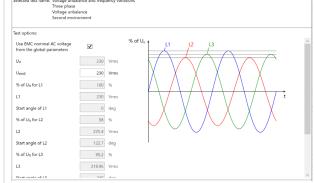
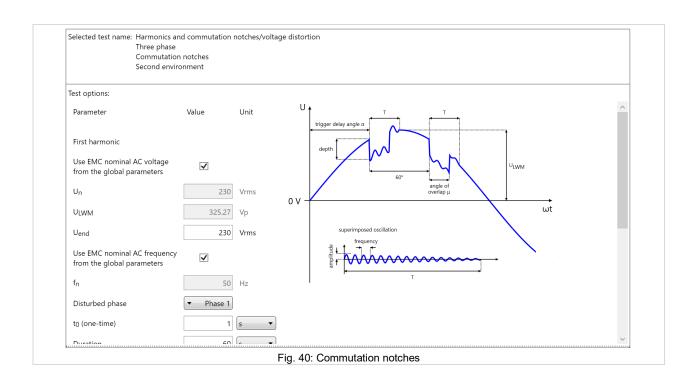


Fig. 39: Voltage unbalance 3-phase







# Software module IEC 62040-2

Automatic testing according to IEC 62040-2:2016 Ed 3.0

- **▲** IEC 62040-2
  - ▶ Edition 2.0 2005-10
  - ▲ Edition 3.0 2016-11
    - Power line harmonics and inter-harmonics

# Single-phase equipment

Three-phase equipment with neutral wire

Three-phase equipment without neutral wire

Power line unbalance (three-phase UPS systems only)
 Amplitude unbalance

Phase unbalance

#### Uninterruptible power systems (UPS)

Integrated functions of the software module:

- control of APS amplifier
- D.6 Immunity to low-frequency signals
- D.6.1 Power line harmonics and inter-harmonics
- D.6.2 Power line unbalance (three-phase UPS systems only)

#### Required hardware:

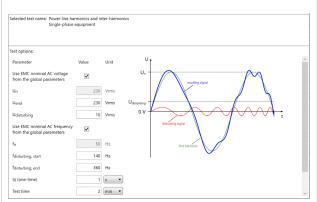


Fig. 41: Harmonics and interharmonics

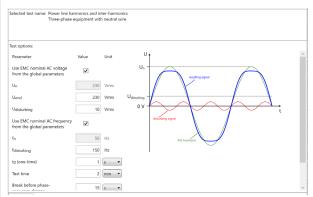


Fig. 42: 3-phase with neutral

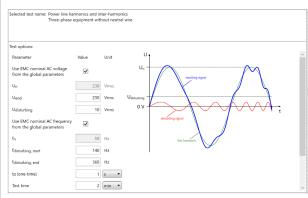


Fig. 43: 3-phase without neutral

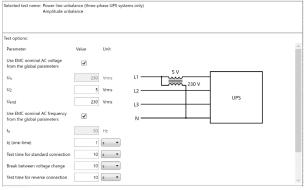


Fig. 44: Amplitude unbalance



# Software module IEC TR 61547-1 Automatic testing according to IEC TR 61547-1:2020 Ed 3.0 Simulation of voltage fluctuations ■ IEC TR 61547-1 ▶ Edition 2.0 2017-10 Integrated functions of the software module: - control of APS amplifier - simulation of voltage fluctuations ■ Edition 3.0 2020-07 ■ Voltage fluctuations Required hardware: 39 cpm at 0.325 Hz 4-quadrant amplifier APS 110 cpm at 0.9167 Hz 1056 cpm at 8.8 Hz 1620 cpm at 13.5 Hz 4000 cpm at 33 ⅓ Hz 4800 cpm at 40 Hz Free adjustable values Selected test name: Voltage fluctuations 1056 cpm at 8.8 Hz Test options: Parameter Value Unit Nominal voltage 230 Vrms End voltage 230 Vrms Nominal frequency 50 Hz Voltage change per minute 1056 cpm Modulation frequency 8.8 Hz Relative voltage fluctuation 0.275 $d = \Delta U/U$ to (one-time) 180 s Test time Fig. 45: Voltage fluctuations



# Software modules under development – available soon...

Simulation of commutation notches
Simulation of commutation noticies
- control of APS amplifier - simulation of commutation notches/ Part 1
Programmable controllers - Part 2: Equipment requirements and tests
- control of APS amplifier - testing with voltage and frequency deviation - superposition of the third harmonic - generation of short voltage dips - generation of continuous changes, slow - generation of continuous changes, partial
Safety of machinery - Electro-sensitive protective equipment - Part 1: General requirements and tests
- control of APS amplifier - 5.4.1 Rated supply voltage (voltage variation, frequency variation and harmonic simulation) - 5.4.3.1 Supply voltage variation - 5.4.3.2 Supply voltage interruptions
a.c. interference on d.c. mains and simulation of harmonics on a.c. mains
- control of APS amplifier - 14.4 Conducted low frequency immunity test
Specification for semiconductor processing equipment voltage sag immunity
- control of APS amplifier - sequential operation of defined pulses - automatic capturing of the waveforms of voltage and current - graphical documentation of the generated voltage dips and/or voltage changes in the test report
Electrical fast transient/burst immunity test
<ul> <li>control of APS amplifier, Multi-CE5</li> <li>generating fast transient disturbances as defined in IEC standard</li> </ul>
Surge immunity test
<ul> <li>control of APS amplifier, Multi-CE5</li> <li>generating fast transient disturbances as defined in IEC standard</li> </ul>